# **BLF573**; **BLF573S**

# HF / VHF power LDMOS transistor Rev. 3 — 8 July 2010

Product data sheet

#### **Product profile** 1.

#### 1.1 General description

A 300 W LDMOS RF power transistor for broadcast applications and industrial, scientific and medical applications in the HF to 500 MHz band.

Table 1. **Production test information** 

Mode of operation	f	V <sub>DS</sub>	P <sub>L</sub>	Gp	η <sub>D</sub>
	(MHz)	(V)	(W)	(dB)	(%)
CW	225	50	300	27.2	70

#### **CAUTION**



This device is sensitive to ElectroStatic Discharge (ESD). Therefore care should be taken during transport and handling.

#### 1.2 Features and benefits

- Typical CW performance at frequency of 225 MHz, a supply voltage of 50 V and an I<sub>Da</sub> of 900 mA:
  - Average output power = 300 W
  - ◆ Power gain = 27.2 dB
  - ◆ Efficiency = 70 %
- Easy power control
- Integrated ESD protection
- Excellent ruggedness
- High efficiency
- Excellent thermal stability
- Designed for broadband operation (HF and VHF band)
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

### 1.3 Applications

- Industrial, scientific and medical applications
- Broadcast transmitter applications



# 2. Pinning information

Table 2. Pinning

BLF573 (SOT502A)  1	ymbol	Graphic sy	е	Simplified outline		Description	Pin
2 gate 3 source  [1]  2 syr  BLF573S (SOT502B)  1 drain 2 gate 3 source [1]						SOT502A)	BLF573 (
3 source [1] 2 2 - syr  BLF573S (SOT502B)  1 drain 2 gate 3 source [1]						drain	1
3 source [1] 2 2 - syr  BLF573S (SOT502B)  1 drain 2 gate 3 source [1]	<u>, 1</u>	ıŀ	)			gate	2
BLF573S (SOT502B)  1		2 — H	)		<u>[1]</u>	source	3
BLF573S (SOT502B)  1	3 m112	svm:					
2 gate 3 source [1]						(SOT502B)	BLF573S
3 source [1]						drain	1
3 source [1]	<u>, 1</u>	ıŀ		1 1		gate	2
		j. 2 − j.			<u>[1]</u>	source	3
	3 m112						

<sup>[1]</sup> Connected to flange.

# 3. Ordering information

Table 3. Ordering information

Type number	Packa	ge	
	Name	Description	Version
BLF573	-	flanged LDMOST ceramic package; 2 mounting holes; 2 leads	SOT502A
BLF573S	-	earless flanged LDMOST ceramic package, 2 leads	SOT502B

# 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage		-	110	V
$V_{GS}$	gate-source voltage		-0.5	+11	V
$I_D$	drain current		-	42	Α
T <sub>stg</sub>	storage temperature		-65	+150	°C
Tj	junction temperature		-	225	°C

# 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions		Тур	Unit
$R_{th(j-c)}$	thermal resistance from junction to case	$T_{case} = 80  ^{\circ}C;  P_{L} = 300  W$	<u>[1]</u>	0.21	K/W

<sup>[1]</sup>  $R_{th(j-c)}$  is measured under RF conditions.

BLF573\_BLF573S

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# 6. Characteristics

Table 6. DC characteristics

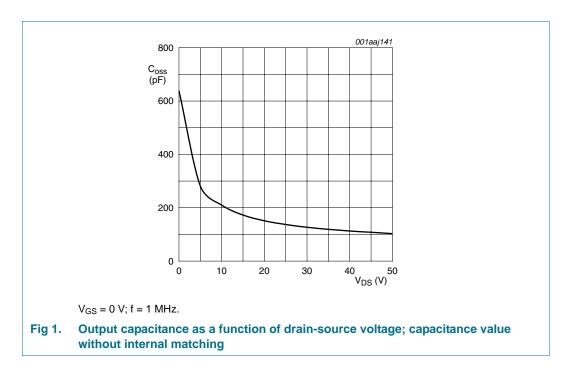
 $T_i = 25$  °C unless otherwise specified.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 3.75 \text{ mA}$	110	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10 \text{ V}; I_D = 375 \text{ mA}$	1.25	1.7	2.25	V
$V_{GSq}$	gate-source quiescent voltage	$V_{DS} = 50 \text{ V}; I_D = 900 \text{ mA}$	1.45	1.95	2.45	V
I <sub>DSS</sub>	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 50 \text{ V}$	-	-	4.2	μΑ
I <sub>DSX</sub>	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$	44	56	-	Α
I <sub>GSS</sub>	gate leakage current	$V_{GS} = 11 \text{ V}; V_{DS} = 0 \text{ V}$	-	-	420	nΑ
g <sub>fs</sub>	forward transconductance	$V_{DS} = 10 \text{ V}; I_D = 18.75 \text{ A}$	-	20	-	S
R <sub>DS(on)</sub>	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 12.49 \text{ A}$	-	0.09	-	Ω
C <sub>rs</sub>	feedback capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 50 \text{ V};$ f = 1 MHz	-	2.3	-	pF
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 50 \text{ V};$ f = 1 MHz	-	300	-	pF
C <sub>oss</sub>	output capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 50 \text{ V};$ f = 1 MHz	-	103	-	pF

#### Table 7. RF characteristics

Mode of operation: CW; f=225 MHz; RF performance at  $V_{DS}=50$  V;  $I_{Dq}=900$  mA;  $T_{case}=25$  °C; unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Gp	power gain	$P_{L} = 300 \text{ W}$	26	27.2	28.4	dB
RLin	input return loss	P <sub>L</sub> = 300 W	10	13	-	dB
$\eta_{D}$	drain efficiency	P <sub>L</sub> = 300 W	67	70	-	%



### 6.1 Ruggedness in class-AB operation

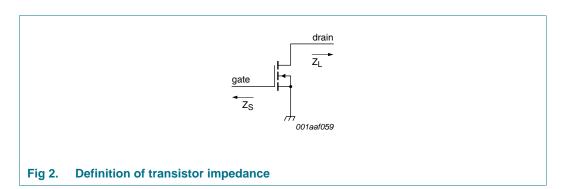
The BLF573 and BLF573S are capable of withstanding a load mismatch corresponding to VSWR = 13 : 1 through all phases under the following conditions:  $V_{DS}$  = 50 V;  $I_{Dq}$  = 900 mA;  $P_L$  = 300 W; f = 225 MHz.

# 7. Application information

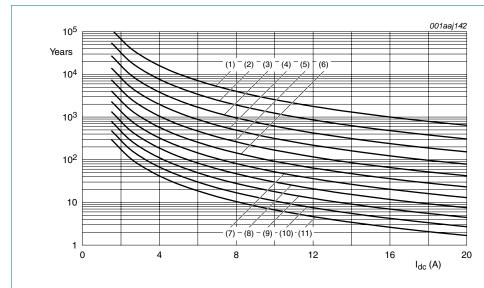
### 7.1 Impedance information

**Table 8. Typical impedance** Measured  $Z_S$  and  $Z_L$  test circuit impedances.

f	Z <sub>S</sub>	Z <sub>L</sub>
MHz	Ω	Ω
225	0.7 + j2.0	1.95 + j2.0



# 7.2 Reliability



TTF (0.1 % failure fraction).

- (1)  $T_j = 100 \, ^{\circ}C$
- (2)  $T_j = 110 \,{}^{\circ}\text{C}$
- (3)  $T_j = 120 \, ^{\circ}C$
- (4)  $T_j = 130 \, ^{\circ}C$
- (5)  $T_i = 140 \, ^{\circ}\text{C}$
- (6)  $T_j = 150 \,^{\circ}\text{C}$
- (7)  $T_j = 160 \, ^{\circ}C$
- (8)  $T_j = 170 \, ^{\circ}C$
- (9)  $T_j = 180 \, ^{\circ}C$
- (10)  $T_j = 190 \, ^{\circ}C$
- (11)  $T_j = 200 \, ^{\circ}C$

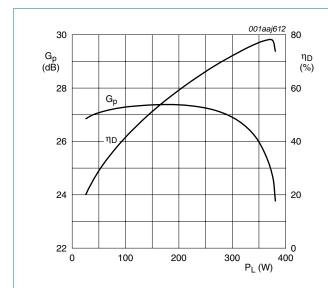
Fig 3. BLF573 and BLF573S electromigration (I<sub>D</sub>, total device)

# 8. Test information

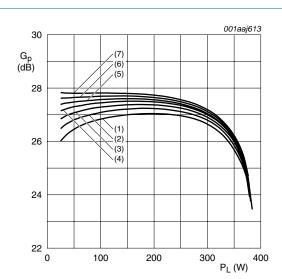
#### 8.1 RF Performance

The following figures are measured in a class-AB production test circuit.

#### 8.1.1 1-Tone CW



 $V_{DS} = 50 \text{ V}; I_{Dq} = 900 \text{ mA}; f = 225 \text{ MHz}.$ 

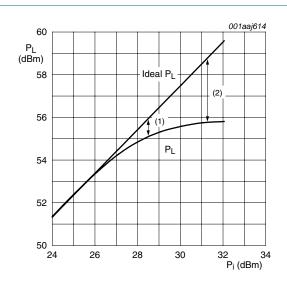


 $V_{DS} = 50 \text{ V}; f = 225 \text{ MHz}.$ 

- (1)  $I_{Dq} = 500 \text{ mA}$
- (2)  $I_{Dq} = 700 \text{ mA}$
- (3)  $I_{Dq} = 900 \text{ mA}$
- (4)  $I_{Dq} = 1100 \text{ mA}$
- (5)  $I_{Dq} = 1300 \text{ mA}$
- (6)  $I_{Dq} = 1500 \text{ mA}$ (7)  $I_{Dq} = 1700 \text{ mA}$

Fig 5. Power gain as function of load power; typical values

Fig 4. Power gain and drain efficiency as functions of load power; typical values

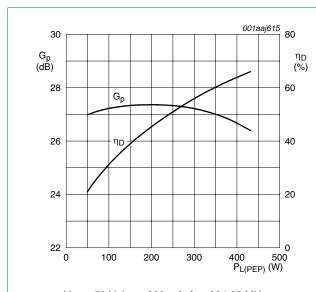


 $V_{DS} = 50 \text{ V}; I_{Dq} = 900 \text{ mA}; f = 225 \text{ MHz}.$ 

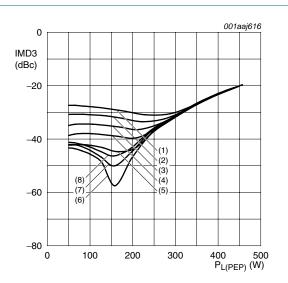
- (1)  $P_{L(1dB)} = 55.2 \text{ dBm } (330 \text{ W})$
- (2)  $P_{L(3dB)} = 55.8 \text{ dBm } (380 \text{ W})$

Fig 6. Load power as function of input power; typical values

#### 8.1.2 2-Tone CW



 $V_{DS}$  = 50 V;  $I_{Dq}$  = 900 mA;  $f_1$  = 224.95 MHz;  $f_2$  = 225.05 MHz.



 $V_{DS} = 50 \text{ V}$ ;  $f_1 = 224.95 \text{ MHz}$ ;  $f_2 = 225.05 \text{ MHz}$ .

- (1)  $I_{Dq} = 500 \text{ mA}$
- (2)  $I_{Dq} = 700 \text{ mA}$
- (3)  $I_{Dq} = 900 \text{ mA}$
- (4)  $I_{Dq} = 1100 \text{ mA}$
- (5)  $I_{Dq} = 1300 \text{ mA}$
- (6)  $I_{Dq} = 1500 \text{ mA}$
- (7)  $I_{Dq} = 1700 \text{ mA}$

(8)  $I_{Dq} = 1800 \text{ mA}$ 

Fig 7. Power gain and drain efficiency as functions of peak envelope load power; typical values

Fig 8. Third order intermodulation distortion as a function of peak envelope load power; typical values

### 8.2 Test circuit

#### Table 9. List of components

For production test circuit, see Figure 9 and Figure 10.

Printed-Circuit Board (PCB): Rogers 5880;  $\varepsilon_r = 2.2$  F/m; height = 0.79 mm; Cu (top/bottom metallization); thickness copper plating = 35  $\mu$ m.

Component	Description	Value	Remarks
B1	ferrite SMD bead	100 Ω; 100 MHz	Ferroxcube BDS3/3/8.9-4S2 or equivalent
C1, C18	multilayer ceramic chip capacitor	100 pF	[1]
C2	multilayer ceramic chip capacitor	39 pF	[1]
C3, C4	multilayer ceramic chip capacitor	180 pF	[1]
C5, C6, C7	multilayer ceramic chip capacitor	220 pF	[1]
C8, C20	multilayer ceramic chip capacitor	1 nF	[1]
C9	multilayer ceramic chip capacitor	4.7 μF	TDK C4532X7R1E475MT020U or equivalent
C10	multilayer ceramic chip capacitor	30 pF	[1]
C11, C12, C13	multilayer ceramic chip capacitor	51 pF	[1]
C14	multilayer ceramic chip capacitor	43 pF	[1]

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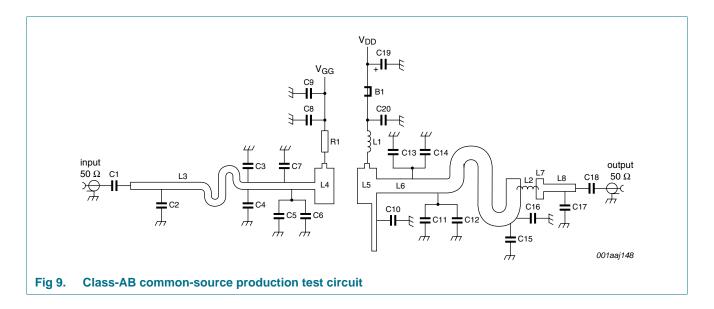
Table 9. List of components ... continued

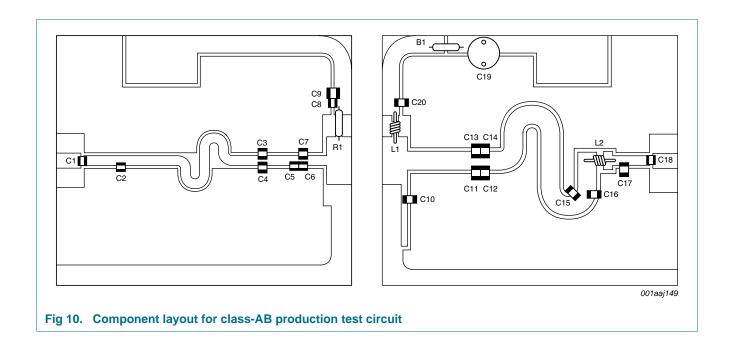
For production test circuit, see Figure 9 and Figure 10.

Printed-Circuit Board (PCB): Rogers 5880;  $\varepsilon_r = 2.2$  F/m; height = 0.79 mm; Cu (top/bottom metallization); thickness copper plating = 35  $\mu$ m.

Component	Description	Value	Remarks
C15	multilayer ceramic chip capacitor	33 pF	Ш
C16	multilayer ceramic chip capacitor	36 pF	[1]
C17	multilayer ceramic chip capacitor	16 pF	П
C19	electrolytic capacitor	220 μF; 63 V	
L1	2 turns enamelled copper wire	D = 3  mm; d = 1  mm; length = 2  mm; $leads = 2 \times 6 \text{ mm}$	
L2	4 turns enamelled copper wire	D = 2 mm; d = 1 mm; length = 13 mm; leads = 2 × 5 mm	
L3	stripline	-	(L $\times$ W) 96 mm $\times$ 3 mm
L4, L5	stripline	-	(L $\times$ W) 15 mm $\times$ 8 mm
L6	stripline	-	(L $\times$ W) 105 mm $\times$ 6 mm
L7	stripline	-	(L $\times$ W) 3 mm $\times$ 6 mm
L8	stripline	-	(L $\times$ W) 12 mm $\times$ 6 mm
R1	metal film resistor	100 Ω; 0.6 W	

[1] American Technical Ceramics type 100B or capacitor of same quality.





# 9. Package outline

#### Flanged LDMOST ceramic package; 2 mounting holes; 2 leads

SOT502A

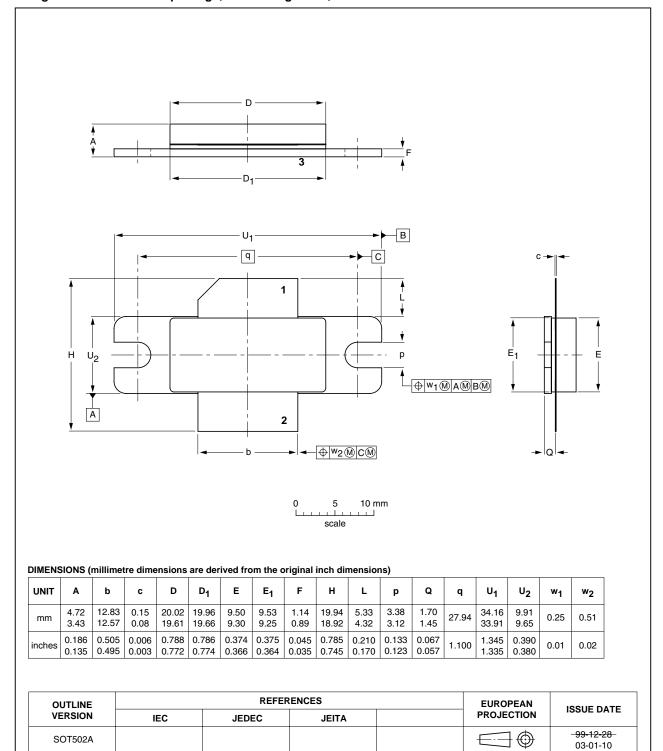


Fig 11. Package outline SOT502A

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#### Earless flanged LDMOST ceramic package; 2 leads

SOT502B

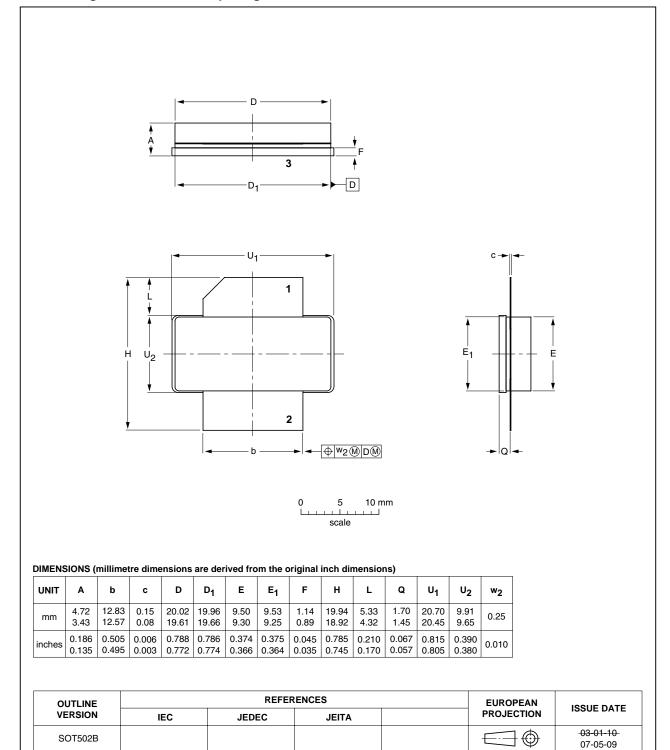


Fig 12. Package outline SOT502B

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# 10. Abbreviations

Table 10. Abbreviations

Acronym	Description
CW	Continuous Wave
EDGE	Enhanced Data rates for GSM Evolution
GSM	Global System for Mobile communications
HF	High Frequency
LDMOS	Laterally Diffused Metal-Oxide Semiconductor
LDMOST	Laterally Diffused Metal-Oxide Semiconductor Transistor
RF	Radio Frequency
SMD	Surface Mount Device
TTF	Time To Failure
VHF	Very High Frequency
VSWR	Voltage Standing-Wave Ratio

# 11. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes	
BLF573_BLF573S v.3	20100708	Product data sheet	-	BLF573S v.2	
Modifications:  • The document now describes both the eared and earless version of this product: BLF573 and BLF573S respectively.					
BLF573S v.2	20090217	Product data sheet	-	BLF573S v.1	
BLF573S v.1	20081208	Preliminary data sheet	-	-	

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Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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- [2] The term 'short data sheet' is explained in section "Definitions"
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#### HF / VHF power LDMOS transistor

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